

Draft American National Standard

**IEEE Trial-Use Standard for
Dielectric Test Requirements for
Power Transformers for Operation at
System Voltages from 115 kV Through 230 kV**

Sponsor

**Transformers Committee of the
IEEE Power Engineering Society**

Secretariat

**Institute of Electrical and Electronics Engineers
National Electrical Manufacturers Association**

Draft American National Standard

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Foreword

(This Foreword is not a part of ANSI/IEEE C57.12.14, IEEE Trial-Use Standard for Dielectric Test Requirements for Power Transformers for Operation at System Voltages from 115 kV Through 230 kV.)

IEEE Std 262B-1977, IEEE Trial-Use Standard Dielectric Test Requirements for Power Transformers for Operation on Effectively Grounded Systems, 345 kV and Above, was published to introduce new concepts in the establishment and verification of dielectric test levels. This standard extends the principles of IEEE Std 262B-1977 down to the 115 kV through 230 kV range of power transformers and, additionally, includes some new considerations in the area of insulation coordination.

The concepts of this standard and those of IEEE Std 262B-1977 are expected to be integrated into ANSI/IEEE C57.12.00-1980 and ANSI/IEEE C57.12.90-1980; both standards cover the subject of transformers.

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